

# DARLINGTON POWER TRANSISTOR 2SD1592

# NPN SILICON TRIPLE DIFFUSED TRANSISTOR (DARLINGTON CONNECTION) FOR HIGH-VOLTAGE LOW-SPEED SWITCHING

#### **FEATURES**

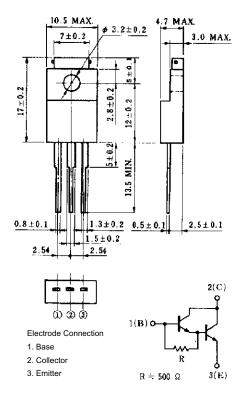
- High DC current gain due to Darlington connection
- · Low collector saturation
- Reverse deterrence type
- Ideal for use in devices such as pulse motor drivers and relay drivers of PC terminals, and ignitors of general-purpose engines.
- Mold package that does not require an insulating board or insulation bushing

#### ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

Parameter	Symbol	Ratings	Unit	
Collector to base voltage	V <sub>СВО</sub>	500	V	
Collector to emitter voltage	VCEO	+300, -10	V	
Emitter to base voltage	V <sub>EBO</sub>	10	V	
Collector current	Ic(DC)	5.0	Α	
Collector current	IC(pulse)*	10	Α	
Base current	I <sub>B(DC)</sub>	0.5	Α	
Total power dissipation	P <sub>T</sub> (Tc = 25°C)	30	W	
Total power dissipation	P⊤ (Ta = 25°C)	1.5	W	
Junction temperature	Tj	150	°C	
Storage temperature	T <sub>stg</sub>	-55 to +150	°C	

<sup>\*</sup> PW  $\leq$  300  $\mu$ s, duty cycle  $\leq$  10%

#### PACKAGE DRAWING (UNIT: mm)



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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.



# **ELECTRICAL CHARACTERISTICS (Ta = 25°C)**

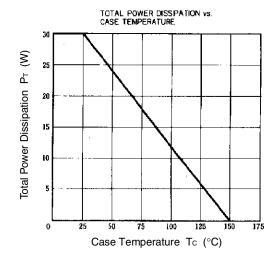
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Collector cutoff current	Ісво	Vcb = 400 V, IE = 0			10	μΑ
DC current gain	h <sub>FE1</sub> *	Vce = 2.0 V, Ic = 2.0 A	400		3,000	
DC current gain	h <sub>FE2</sub> *	Vce = 2.0 V, Ic = 3.0 A	100			
Collector saturation voltage	V <sub>CE(sat)</sub> *	Ic = 2 A, I <sub>B</sub> = 5 mA		1.0	1.5	V
Base saturation voltage	V <sub>BE(sat)</sub> *	Ic = 2 A, I <sub>B</sub> = 5 mA		1.6	2.0	V
Turn-on time	ton	Ic = 3.0 A, I <sub>B1</sub> = $-I_{B2}$ = 30 mA R <sub>L</sub> = 50 $\Omega$ , Vcc $\cong$ 150 V		1.0		μs
Storage time	tstg			12		μs
Fall time	t <sub>f</sub>			6		μs

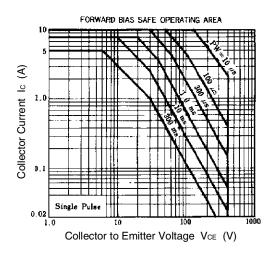
<sup>\*</sup> Pulse test PW  $\leq$  350  $\mu$ s, duty cycle  $\leq$  2%

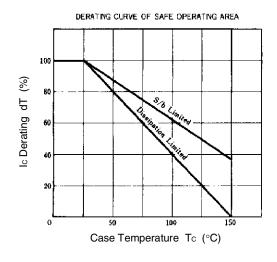
### **hfe CLASSIFICATION**

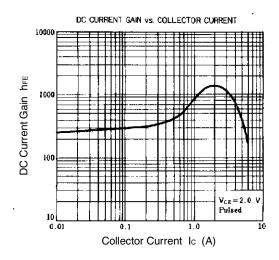
Marking	М	L	К
hfe	400 to 800	600 to 1,200	1,000 to 3,000

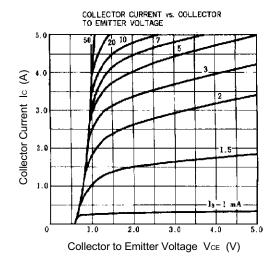
# TYPICAL CHARACTERISTICS (Ta = 25°C)

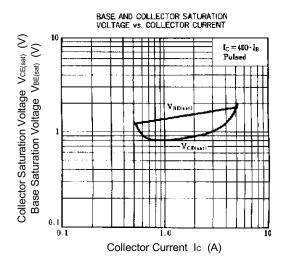












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